

Precision tests of third-generation four-quark SMEFT operators

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In the framework of the SMEFT we derive the indirect constraints on third-generation four-quark operators that arise from electroweak precision measurements as well as flavour physics. To this purpose we calculate the dominant one- and two-loop contributions to the observables in question. We find that the considered loop effects can lead to better constraints than those from fits to top-quark data collected at the LHC.

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